

<b>Notice of References Cited</b>	Application/Control No. 10/750,154	Applicant(s)/Patent Under Reexamination BAINS ET AL.	
	Examiner Lev I. Iwashko	Art Unit 2186	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,151,271	11-2000	Lee, Jung-bae	365/233
*	B	US-6,279,116	08-2001	Lee, Ho-Cheol	713/601
*	C	US-5,721,874	02-1998	Carnevale et al.	711/171
*	D	US-5,448,310	09-1995	Kopet et al.	348/699
*	E	US-6,721,864	04-2004	Keskar et al.	711/167
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IBM Technical Disclosure Bulletin, "Bit Vector Algorithm for Detecting Self-Modification in Data Chains", October 1, 1989, Vol. 32, Issue 5A, pp. 455-457 (5 pages included in printout).
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.